**Product data sheet** 

## 1. General description

High voltage high speed planar passivated NPN power switching transistor in a SOT428 (DPAK) surface mountable plastic package.

### 2. Features and benefits

- Fast switching
- · Low thermal resistance
- Surface mountable package
- · Tight DC gain spreads
- Very high voltage capability
- · Very low switching and conduction losses

## 3. Applications

- DC-to-DC converters
- · High frequency electronic lighting ballasts
- Inverters
- Motor control systems

## 4. Pinning information

**Table 1. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	В	base	mb	С
2	С	collector[1]		В
3	E	emitter		
mb	С	mounting base; connected to collector	1 3 DPAK (SOT428)	Ë sym123

[1] it is not possible to make a connection to pin 2 of the SOT428 (DPAK) package.

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# 5. Ordering information

### **Table 2. Ordering information**

Type number	Package				
	Name	Description	Version		
BUJ303CD	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428		

# 6. Marking

### **Table 3. Marking codes**

Type number	Marking code
BUJ303CD	BUJ303CD

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## 7. Limiting values

### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CESM</sub>	collector-emitter peak voltage	V <sub>BE</sub> = 0 V	-	1050	V
$V_{CEO}$	collector-emitter voltage	I <sub>B</sub> = 0 A	-	400	V
I <sub>C</sub>	collector current	Fig. 1; Fig. 2; Fig. 3	-	5	Α
I <sub>CM</sub>	peak collector current		-	10	Α
$I_{B}$	base current		-	2	Α
I <sub>BM</sub>	peak base current		-	4	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> ≤ 25 °C; <u>Fig. 4</u>	-	80	W
T <sub>stg</sub>	storage temperature		-65	150	°C
Tj	junction temperature		-	150	°C

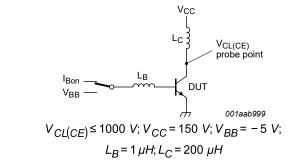


Fig. 1. Test circuit for reverse bias safe operating area

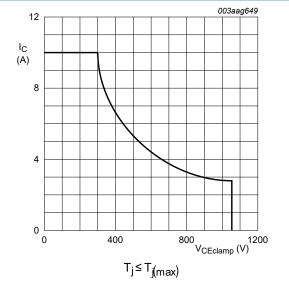
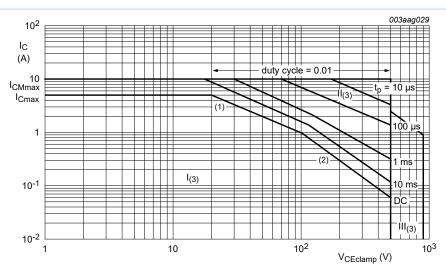


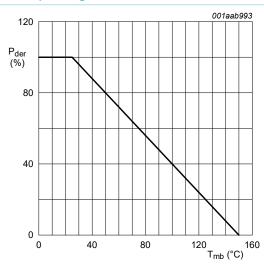
Fig. 2. Reverse bias safe operating area

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- (1) P<sub>tot</sub> maximum and P<sub>tot</sub> peak maximum lines.
- (2) Second breakdown limits.
- (3) I = Region of permissible DC operation.
- II = Extension for repetitive pulse operation.
- III = Extension during turn-on in single transistor converters provided that  $R_{BE} \le 100 \Omega$  and  $t_p \le 0.6 \mu s$ .

Fig. 3. Forward bias safe operating area for Tmb ≤ 25 °C



$$P_{der} = \frac{P_{tot}}{P_{tot}(25^{\circ}C)} \times 100\%$$

Fig. 4. Normalized total power dissipation as a function of mounting base temperature

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### 8. Thermal characteristics

**Table 5. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 5	-	-	1.56	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient free air	printed circuit board (FR4) mounted; minimum footprint; Fig. 6	-	75	-	K/W

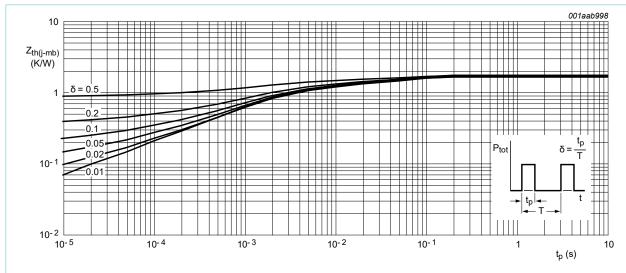
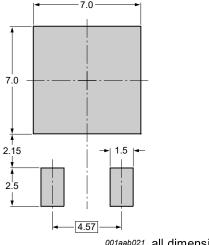


Fig. 5. Transient thermal impedance from junction to mounting base as a function of pulse width



001aab021 all dimensions are in mm

Fig. 6. Minimum footprint SOT428

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### 9. Characteristics

#### **Table 6. Characteristics**

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static chara	cteristics						
I <sub>CES</sub>	collector-emitter cut-off	V <sub>BE</sub> = 0 V; V <sub>CE</sub> = 1050 V	[1]	-	-	1	mA
	current (base shorted)	V <sub>BE</sub> = 0 V; V <sub>CE</sub> = 1050 V; T <sub>j</sub> = 125 °C	[1]	-	-	2	mA
I <sub>CBO</sub>	collector-base cut-off current (emitter open)	$V_{CB} = 1050 \text{ V}; I_{E} = 0 \text{ A}; T_{mb} = 25 \text{ °C}$	[1]	-	-	1	mA
I <sub>CEO</sub>	collector-emitter cut-off current (base open)	$V_{CE} = 400 \text{ V}; I_{B} = 0 \text{ A}; T_{mb} = 25 \text{ °C}$	[1]	-	-	0.1	mA
I <sub>EBO</sub>	emitter-base cut-off current (collector open)	$V_{EB} = 9 \text{ V}; I_{C} = 0 \text{ A}; T_{mb} = 25 \text{ °C}$		-	-	0.1	mA
$V_{CEOsus}$	collector-emitter sustaining voltage (base open)	$I_B = 0 \text{ A}; I_C = 100 \text{ mA}; L_C = 25 \text{ mH};$ $T_{mb} = 25 ^{\circ}\text{C}; \frac{\text{Fig. 7}}{\text{Fig. 8}}; \frac{8}{\text{Fig. 8}}$		400	-	-	V
V <sub>CEsat</sub>	collector-emitter saturation voltage	$I_C = 1 \text{ A}; I_B = 0.2 \text{ A}; T_{mb} = 25 \text{ °C}; Fig. 9; Fig. 10$		-	-	0.5	V
		$I_C = 3 \text{ A}; I_B = 1 \text{ A}; T_{mb} = 25 \text{ °C}; Fig. 9; Fig. 10$		-	0.25	1.5	V
$V_{BEsat}$	base-emitter saturation voltage	$I_C = 3 \text{ A}; I_B = 1 \text{ A}; T_{mb} = 25 \text{ °C}; Fig. 11$		-	1	1.5	V
h <sub>FE</sub>	DC current gain	$I_C$ = 10 mA; $V_{CE}$ = 3 V; $T_{mb}$ = 25 °C; Fig. 12		28	34	47	
		$I_C$ = 250 mA; $V_{CE}$ = 3 V; $T_{mb}$ = 25 °C; Fig. 12		35	43	57	
		$I_C$ = 800 mA; $V_{CE}$ = 3 V; $T_{mb}$ = 25 °C; Fig. 12		31	37	48	
Dynamic ch	aracteristics (switching tir	nes - resistive load)					
t <sub>on</sub>	turn-on time	I <sub>C</sub> = 2.5 A; I <sub>Bon</sub> = 0.5 A; I <sub>Boff</sub> = -1 A;		-	1	-	μs
t <sub>s</sub>	storage time	storage time $R_L = 100 \Omega; T_j = 25 ^{\circ}C; Fig. 13; Fig. 14$ fall time		-	2.5	-	μs
t <sub>f</sub>	fall time			-	0.3	-	μs
Dynamic ch	aracteristics (switching tir	nes - inductive load)		-	1	1	1
t <sub>s</sub>	storage time	I <sub>C</sub> = 2.5 A; I <sub>Bon</sub> = 0.5 A; V <sub>BB</sub> = -5 V; L <sub>B</sub> = 1 μH; T <sub>j</sub> = 25 °C; <u>Fig. 15</u> ; <u>Fig. 16</u>		-	2	-	μs
		$I_C$ = 2.5 A; $I_{Bon}$ = 0.5 A; $V_{BB}$ = -5 V; $L_B$ = 1 $\mu$ H; $T_j$ = 100 °C; <u>Fig. 15</u> ; <u>Fig. 16</u>		-	3	-	μs
t <sub>f</sub>	fall time	I <sub>C</sub> = 2.5 A; I <sub>Bon</sub> = 0.5 A; V <sub>BB</sub> = -5 V; L <sub>B</sub> = 1 μH; T <sub>j</sub> = 25 °C; <u>Fig. 15</u> ; <u>Fig. 16</u>		-	200	-	ns
		I <sub>C</sub> = 2.5 A; I <sub>Bon</sub> = 0.5 A; V <sub>BB</sub> = -5 V; L <sub>B</sub> = 1 μH; T <sub>i</sub> = 100 °C; <u>Fig. 15</u> ; <u>Fig. 16</u>		-	300	-	ns

<sup>[1]</sup> Measured with half-sine wave voltage (curve tracer).

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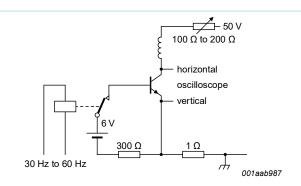


Fig. 7. Test circuit for collector-emitter sustaining voltage

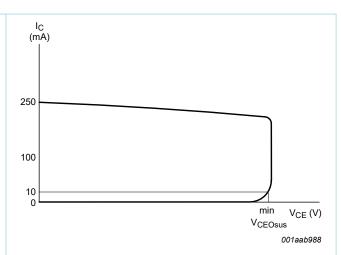


Fig. 8. Oscilloscope display for collector-emitter sustaining voltage test waveform

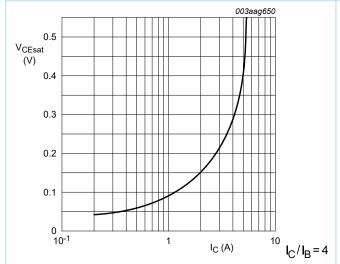


Fig. 9. Collector-emitter saturation voltage as a function of collector current; typical values

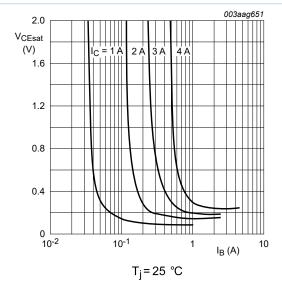


Fig. 10. Collector-emitter saturation voltage as a function of base current; typical values

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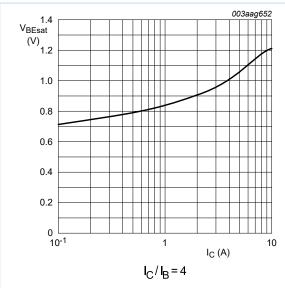


Fig. 11. Base-emitter saturation voltage as a function of collector current; typical values

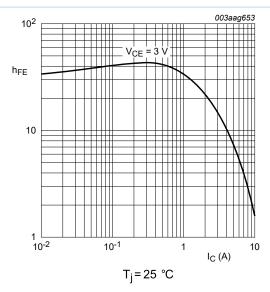
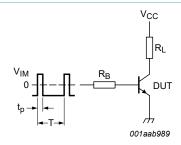


Fig. 12. DC current gain as a function of collector current; typical values



 $V_{IM}$  = -6 to +8 V;  $V_{CC}$  = 250 V;  $t_p$  = 20  $\mu$ s;  $\delta$  =  $\frac{t_p}{T}$  = 0.01  $R_B$  and  $R_L$  calculated from  $I_{Con}$  and  $I_{Bon}$  requirements.

Fig. 13. Test circuit for resistive load switching

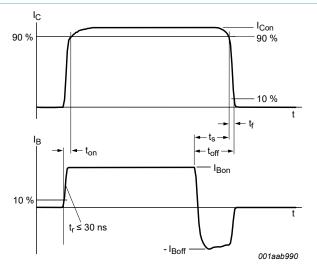
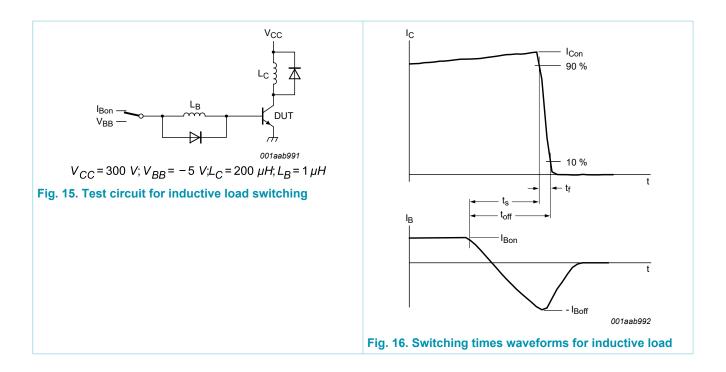


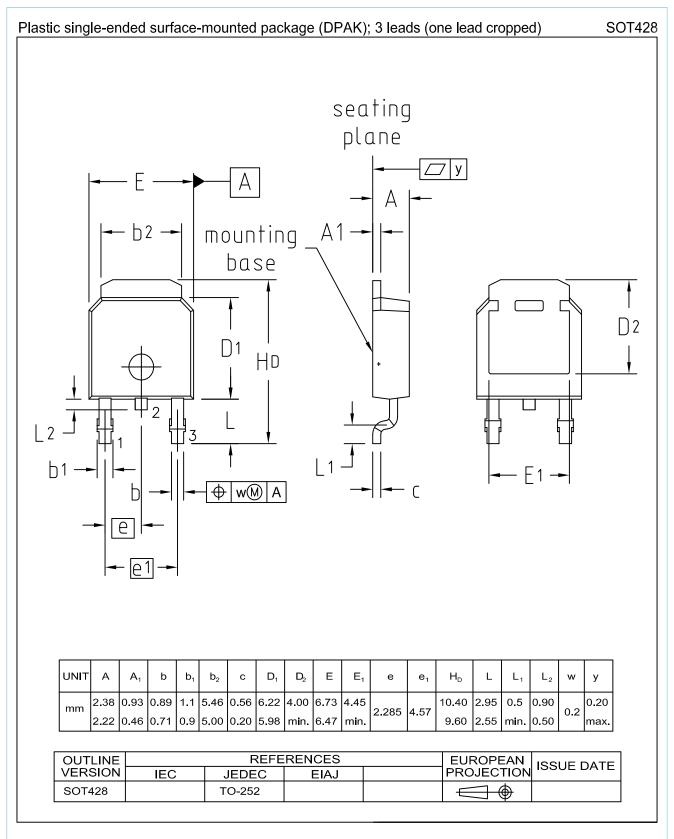
Fig. 14. Switching times waveforms for resistive load

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## 10. Package outline



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# 11. Legal information

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Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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## BUJ303CD

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